IN THE U.S. PATENT AND TRADEMARK OFFICE

In re application of

Seiichi SAITO et al.

Conf.

Application No. NEW NATIONAL PHASE

Group

Filed December 14, 2004

Examiner

EPOXY RESIN COMPOSITION

INFORMATION DISCLOSURE STATEMENT (SUBMISSION CONCURRENT WITH THE FILING OF A NEW PATENT APPLICATION)

Assistant Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

December 14, 2004

Sir:

Pursuant to 37 C.F.R. §§ 1.97 and 1.98, and in fulfillment of the duty of disclosure under 37 C.F.R. § 1.56, applicant(s) hereby submit(s) an Information Disclosure Statement for consideration by the Examiner.

I. LIST OF PATENTS, PUBLICATIONS OR OTHER INFORMATION

The patents, publications, or other information submitted for consideration by the Office are listed on PTO-1449, attached hereto.

II. COPIES

- Copies of the U.S. patents or publications are not submitted since the USPTO has waived their submission for applications filed after June 30, 2003.
- Submitted herewith is a legible copy of (i) each foreign patent; (ii) each publication or that portion which caused it to be listed; and (iii) all other information or that portion which caused it to be listed.
- This application is a National Phase of a PCT application. Some or all of the documents listed on the PTO-1449 are not enclosed because they were cited in the International Search Report and copies should have been forwarded from the International Search Authority pursuant to the trilateral agreement between the USPTO, EPO and JPO, or they are U.S. patents or U.S. published applications. If copies are needed, please contact the undersigned.

III.			RPLANATION OF THE RELEVANCE DT05 Rec'd PCT/PTO 1 4 DEC 2004
	a.		DOCUMENTS IN THE ENGLISH LANGUAGE
			The attached non U.S. patents, non U.S. patent application publications, foreign publications, or other information in the English language do not require a statement of relevancy.
	b.		DOCUMENTS NOT IN THE ENGLISH LANGUAGE
			A concise explanation of the relevance of all patents, publications, or other information listed that is not in the English language is as follows:
	c.	\boxtimes	FOREIGN SEARCH REPORT OR ACTION
			An English language version of the search report or action that indicates the degree of relevance found by the foreign office is attached, thereby satisfying the requirement for a concise explanation. See MPEP 609(A)(3).
	d.		OTHER
			The following additional information is provided for the Examiner's consideration.
			FEES
concu there	This errent fore,	Inf ly y	ormation Disclosure Statement is being filed with the filing of a new patent application; see is required.
is re	If Thequest	ne Ex	aminer has any questions concerning this IDS, he/she contact the undersigned.
			Respectfully submitted,
			YOUNG & THOMPSON
			Benoît Castel
			Benoit Castel, Reg. No. 35,041 745 South 23 rd Street Arlington, VA 22202 Telephone (703) 521-2297 Telefax (703) 685-0573 (703) 979-4709
BC/yr	:		
Enclo	sures	3:	<pre> Form PTO-1449(s) Documents </pre>
			Foreign Search Report Other:

10/518008

Attorney Docket	No.:
8007-1079	

NEW NATIONAL PHASE

INFORMATION DISCLOSURE CITATION IN AN APPLICATION

(Use several sheets if necessary)

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Filing Date: December 14, 2004

Group Art Unit:

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing date (if appropriate)
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FOREIGN PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	2001-354836	12/25/2001	JAPAN				
	633295	1/11/1995	EUROPE				
	8-20671	1/23/1996	JAPAN				
	10-316428	12/2/1998	JAPAN				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER:

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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

^{*} English language abstract provided for the Examiner's convenience